



Description

The XPX028N03FD uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.

$V_{DS} = 30V, I_D = 100A$

$R_{DS(ON)} = 2.8m\Omega$ (typ) @ $V_{GS} = 10V$

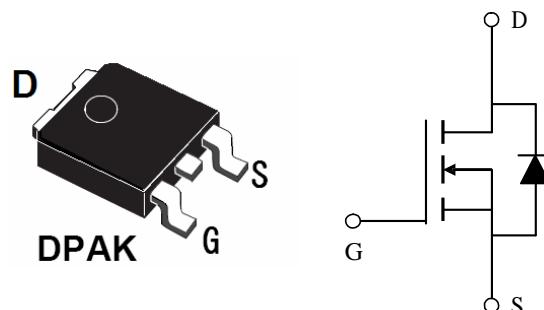
$R_{DS(ON)} = 4.5m\Omega$ (typ) @ $V_{GS} = 4.5V$

General Features

- High density cell design for ultra low $R_{DS(ON)}$
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation

Application

- PWM
- Load Switching

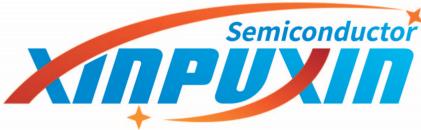


Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
XPX028N03FD	XPX028N03FD	DFN 3x3-8	-	-	5000

Absolute Maximum Ratings ($T_C = 25^\circ C$ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V_{DS}	30	V
Gate-Source Voltage	V_{GS}	± 20	V
Drain Current-Continuous	I_D	100	A
Drain Current-Continuous($T_C = 100^\circ C$)	$I_D (100^\circ C)$	65	A
Pulsed Drain Current ^(Note 1)	I_{DM}	350	A
Maximum Power Dissipation	P_D	70	W
Derating factor		3.2	W/ $^\circ C$
Single pulse avalanche energy ^(Note 5)	E_{AS}	121	mJ
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55 To 150	$^\circ C$
Thermal Resistance, Junction-to-Case ^(Note 2)	$R_{\theta JC}$	2.15	$^\circ C/W$

**Electrical Characteristics** ($T_A = 25^\circ\text{C}$ unless otherwise noted)

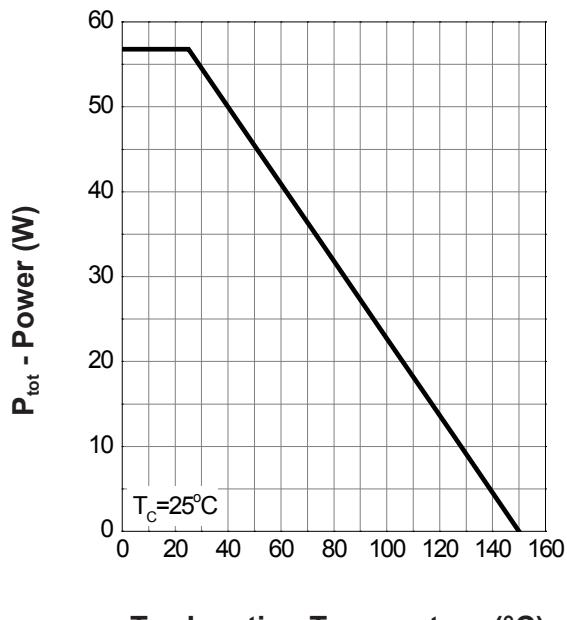
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
Static Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}, I_{\text{DS}}=250\mu\text{A}$	30	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{\text{DS}}=24\text{V}, V_{\text{GS}}=0\text{V}$	-	-	1	μA
		$T_J=85^\circ\text{C}$	-	-	30	
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{DS}}=250\mu\text{A}$	1.0	1.5	2.5	V
I_{GSS}	Gate Leakage Current	$V_{\text{GS}}=\pm 20\text{V}, V_{\text{DS}}=0\text{V}$	-	-	± 100	nA
$R_{\text{DS(ON)}}^{\text{d}}$	Drain-Source On-state Resistance	$V_{\text{GS}}=10\text{V}, I_{\text{DS}}=20\text{A}$	-	2.8	3.8	$\text{m}\Omega$
		$T_J=125^\circ\text{C}$	-	4.4	-	
		$V_{\text{GS}}=4.5\text{V}, I_{\text{DS}}=20\text{A}$	-	4.5	5.5	
G_{fs}	Forward Transconductance	$V_{\text{DS}}=5\text{V}, I_{\text{DS}}=20\text{A}$	-	24.6	-	S
Diode Characteristics						
V_{SD}^{d}	Diode Forward Voltage	$I_{\text{SD}}=20\text{A}, V_{\text{GS}}=0\text{V}$	-	0.8	1.1	V
t_r	Reverse Recovery Time	$I_{\text{DS}}=20\text{A}, dI_{\text{SD}}/dt=100\text{A}/\mu\text{s}$	-	35.6	-	ns
t_a	Charge Time		-	19.3	-	
t_b	Discharge Time		-	16.3	-	
Q_{rr}	Reverse Recovery Charge		-	26	-	nC
Dynamic Characteristics ^e						
R_G	Gate Resistance	$V_{\text{GS}}=0\text{V}, V_{\text{DS}}=0\text{V}, f=1\text{MHz}$	-	1	2	Ω
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}, V_{\text{DS}}=15\text{V}, \text{Frequency}=1.0\text{MHz}$	-	1968	2818	pF
C_{oss}	Output Capacitance		-	850	-	
C_{rss}	Reverse Transfer Capacitance		-	185	-	
$t_{\text{d(ON)}}$	Turn-on Delay Time	$V_{\text{DD}}=15\text{V}, R_L=15\Omega, I_{\text{DS}}=1\text{A}, V_{\text{GEN}}=10\text{V}, R_G=6\Omega$	-	12.4	23	ns
t_r	Turn-on Rise Time		-	9.5	18	
$t_{\text{d(OFF)}}$	Turn-off Delay Time		-	27.2	49	
t_f	Turn-off Fall Time		-	35.2	64	
Gate Charge Characteristics ^e						
Q_g	Total Gate Charge	$V_{\text{DS}}=15\text{V}, V_{\text{GS}}=10\text{V}, I_{\text{DS}}=20\text{A}$	-	20.6	28.8	nC
Q_g	Total Gate Charge	$V_{\text{DS}}=15\text{V}, V_{\text{GS}}=4.5\text{V}, I_{\text{DS}}=20\text{A}$	-	9.8	-	
Q_{gth}	Threshold Gate Charge		-	1.8	-	
Q_{gs}	Gate-Source Charge		-	3.8	-	
Q_{gd}	Gate-Drain Charge		-	3.7	-	

Note d : Pulse test ; pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.

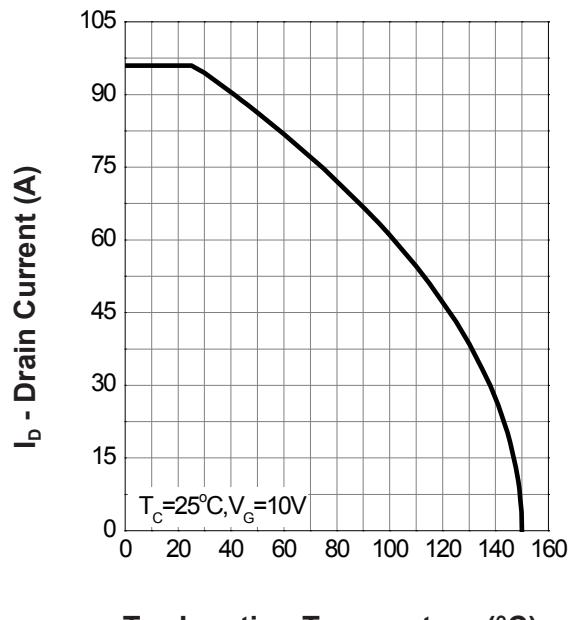
Note e : Guaranteed by design, not subject to production testing.

Typical Operating Characteristics

Power Dissipation



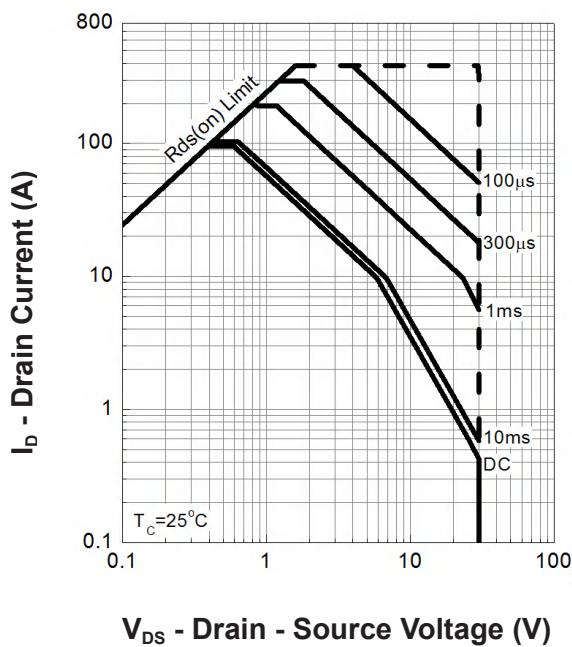
Drain Current



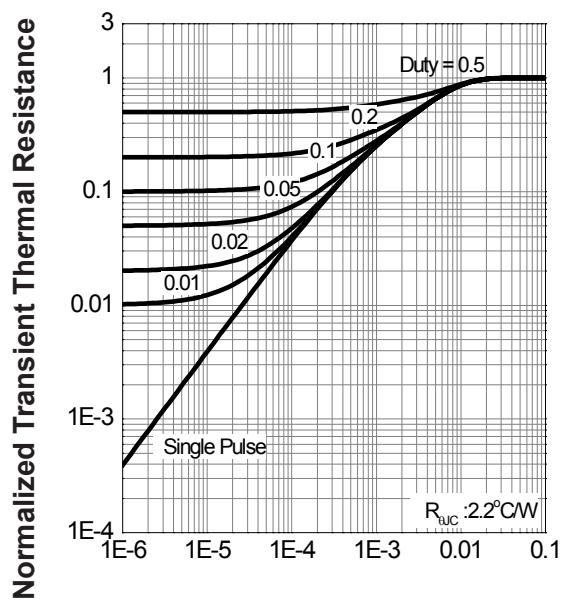
T_j - Junction Temperature (°C)

T_j - Junction Temperature (°C)

Safe Operation Area



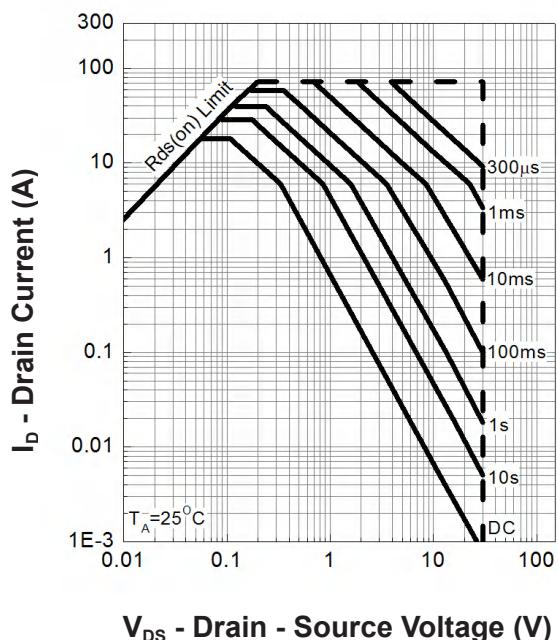
Thermal Transient Impedance



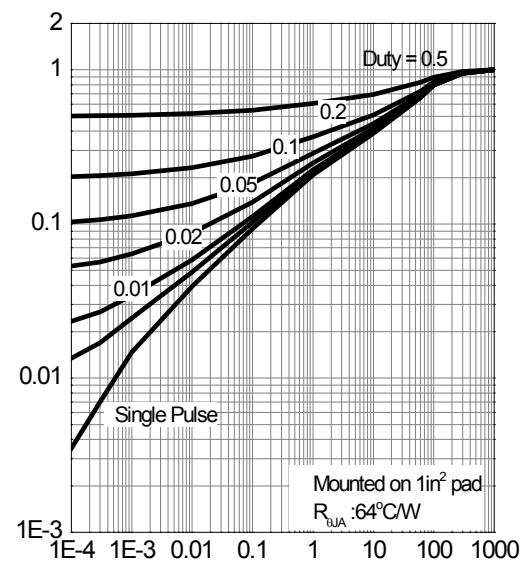
Square Wave Pulse Duration (sec)

Typical Operating Characteristics(Cont.)

Safe Operation Area



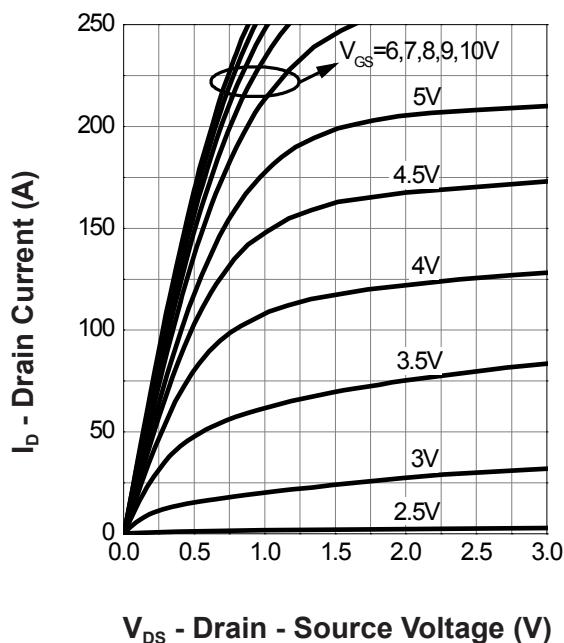
Thermal Transient Impedance



V_{DS} - Drain - Source Voltage (V)

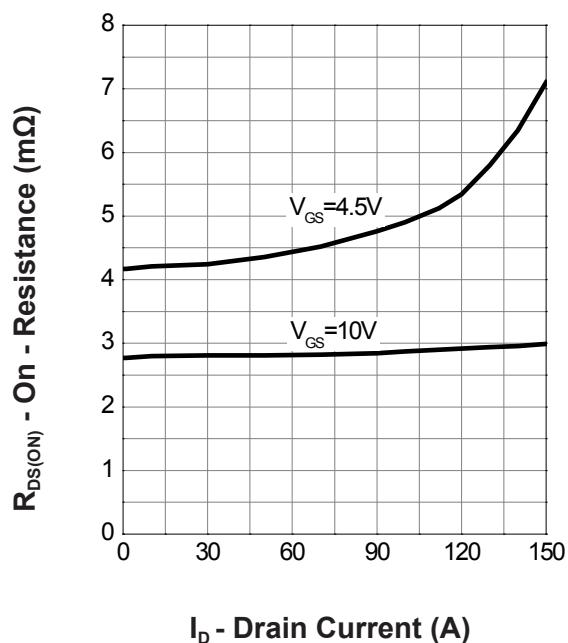
Square Wave Pulse Duration (sec)

Output Characteristics



V_{DS} - Drain - Source Voltage (V)

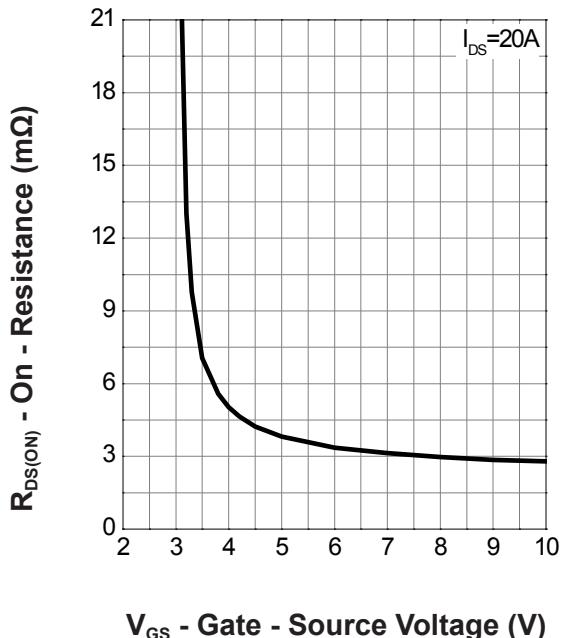
Drain-Source On Resistance



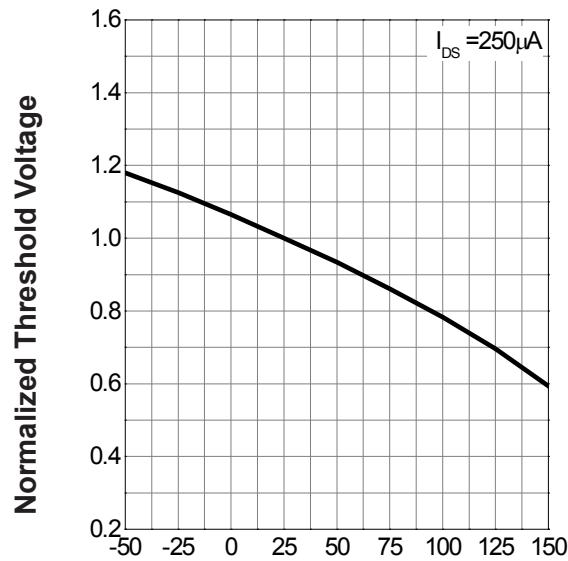
I_D - Drain Current (A)

Typical Operating Characteristics(Cont.)

Gate-Source On Resistance



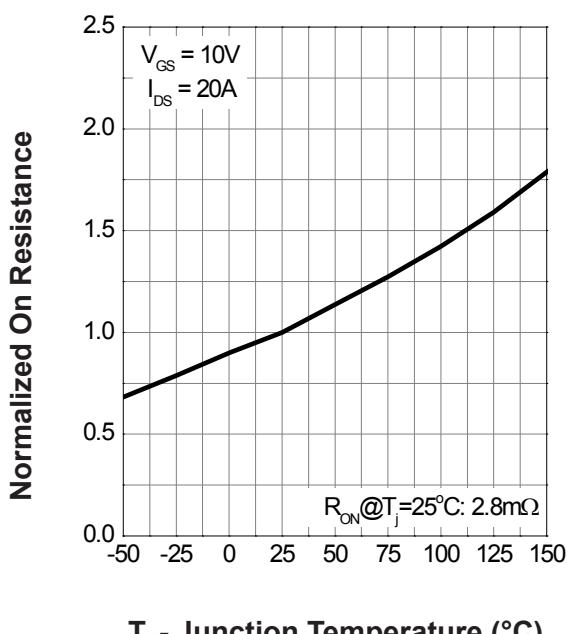
Gate Threshold Voltage



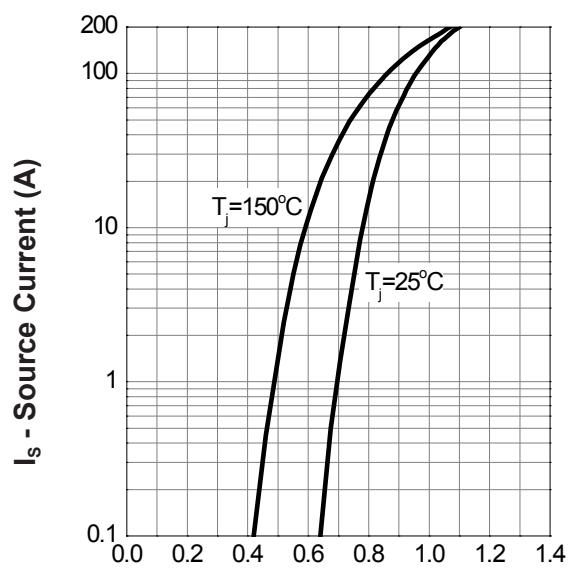
V_{GS} - Gate - Source Voltage (V)

T_j - Junction Temperature (°C)

Drain-Source On Resistance



Source-Drain Diode Forward

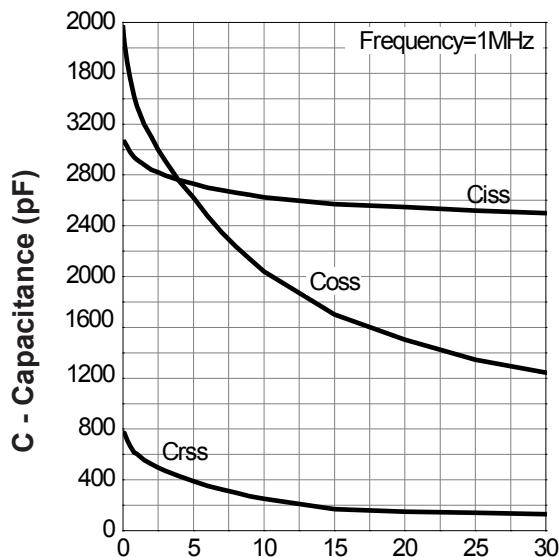


T_j - Junction Temperature (°C)

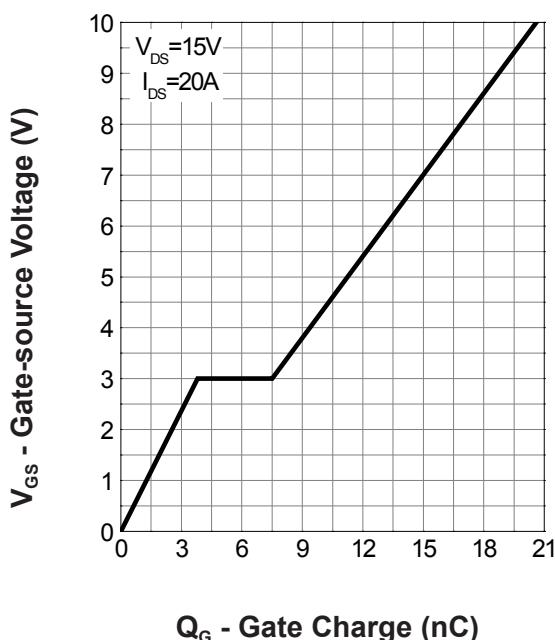
V_{SD} - Source - Drain Voltage (V)

Typical Operating Characteristics(Cont.)

Capacitance



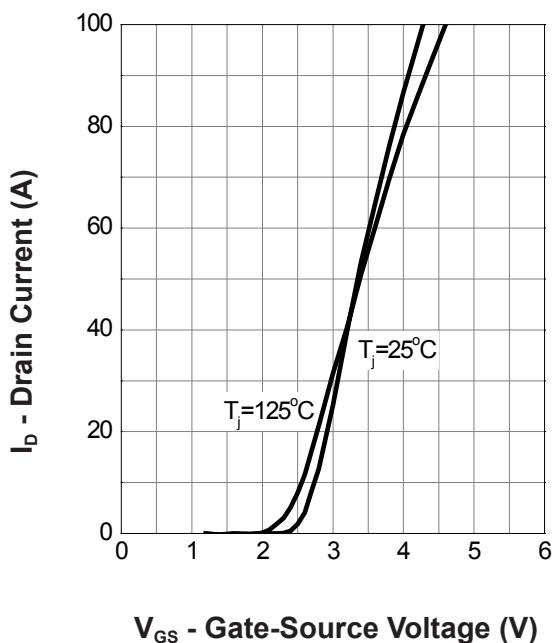
Gate Charge



V_{DS} - Drain-Source Voltage (V)

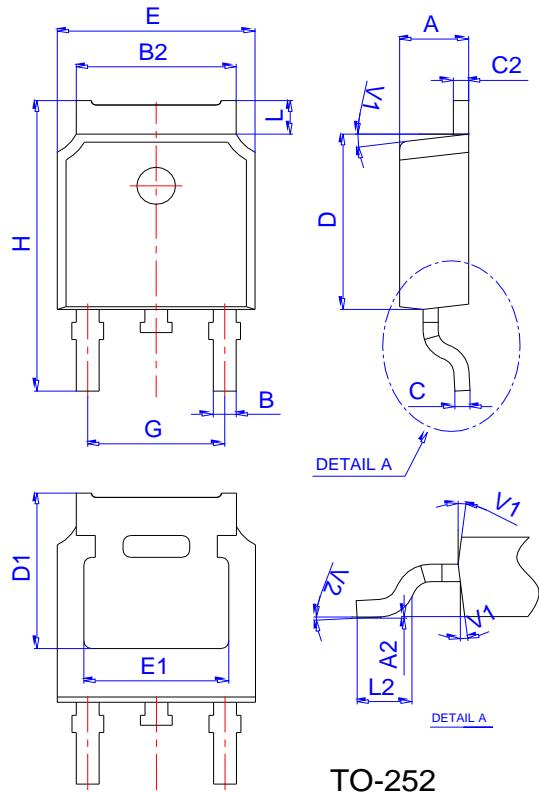
Q_G - Gate Charge (nC)

Transfer Characteristics



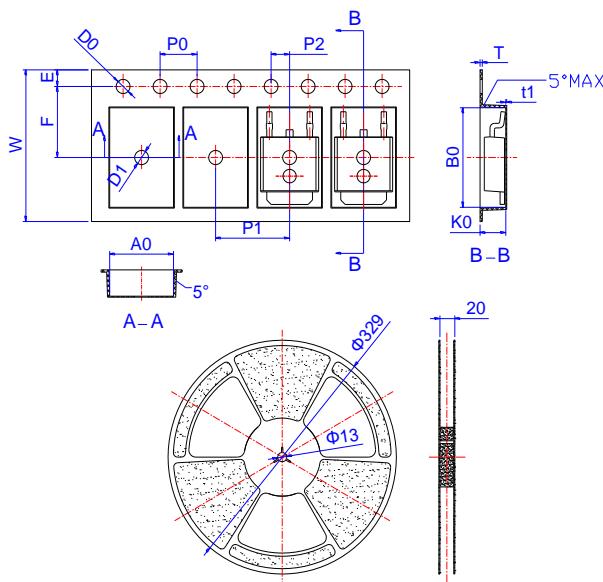
V_{GS} - Gate-Source Voltage (V)

Package Mechanical Data:TO-252-3L



Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	2.10		2.50	0.083		0.098
A2	0		0.10	0		0.004
B	0.66		0.86	0.026		0.034
B2	5.18		5.48	0.202		0.216
C	0.40		0.60	0.016		0.024
C2	0.44		0.58	0.017		0.023
D	5.90		6.30	0.232		0.248
D1	5.30REF			0.209REF		
E	6.40		6.80	0.252		0.268
E1	4.63			0.182		
G	4.47		4.67	0.176		0.184
H	9.50		10.70	0.374		0.421
L	1.09		1.21	0.043		0.048
L2	1.35		1.65	0.053		0.065
V1		7°			7°	
V2	0°		6°	0°		6°

Reel Specification-TO-252



Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
W	15.90	16.00	16.10	0.626	0.630	0.634
E	1.65	1.75	1.85	0.065	0.069	0.073
F	7.40	7.50	7.60	0.291	0.295	0.299
D0	1.40	1.50	1.60	0.055	0.059	0.063
D1	1.40	1.50	1.60	0.055	0.059	0.063
P0	3.90	4.00	4.10	0.154	0.157	0.161
P1	7.90	8.00	8.10	0.311	0.315	0.319
P2	1.90	2.00	2.10	0.075	0.079	0.083
A0	6.85	6.90	7.00	0.270	0.271	0.276
B0	10.45	10.50	10.60	0.411	0.413	0.417
K0	2.68	2.78	2.88	0.105	0.109	0.113
T	0.24		0.27	0.009		0.011
t1	0.10			0.004		
10P0	39.80	40.00	40.20	1.567	1.575	1.583

Flow (wave) soldering (solder dipping)

Product	Peak Temperature	Dipping Time
Pb device	245°C±5°C	5sec±1sec
Pb-Free device	260°C+0/-5°C	5sec±1sec



This integrated circuit can be damaged by ESD. UniverChip Corporation recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedure can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

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